Applicant(s)/Patent Under Application/Control No. Reexamination 10/014,737 TANAKA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1637 Jeffrey Siew **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 435/ US-Besever et al Α 8-1999 В US-С US-D US-E US-F US-US-G US-Н

FOREIGN PATENT DOCUMENTS

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